

512 Kbit / 1 Mbit / 2 Mbit Serial Flash

SST45VF512 / SST45VF010 / SST45VF020



Advance Information

FEATURES:

- **Single 2.7-3.6V Read and Write Operations**
- **Serial Interface Architecture**
 - SPI Compatible: Mode 0 and Mode 3
- **Byte Serial Read with Single Command**
- **Superior Reliability**
 - Endurance: 100,000 Cycles (typical)
 - Greater than 100 years Data Retention
- **Low Power Consumption:**
 - Active Current: 20 mA (typical)
 - Standby Current: 10 μ A (typical)
- **Sector or Chip-Erase Capability**
 - Uniform 4 KByte sectors
- **Fast Erase and Byte-Program:**
 - Chip-Erase Time: 70 ms (typical)
 - Sector-Erase Time: 18 ms (typical)
 - Byte-Program Time: 14 μ s (typical)
- **Automatic Write Timing**
 - Internal V_{PP} Generation
- **End-of-Write Detection**
 - Software Status
- **10 MHz Max Clock Frequency**
- **Hardware Reset Pin (RESET#)**
 - Resets the device to Standby Mode
- **CMOS I/O Compatibility**
- **Hardware Data Protection**
 - Protects and unprotects the device from Write operation
- **Packages Available**
 - 8-Pin SOIC (4.9mm x 6mm)

PRODUCT DESCRIPTION

The SST45VF512, SST45VF010 and SST45VF020 are manufactured with SST's proprietary, high performance CMOS SuperFlash technology. The Serial Flash is organized as 16 sectors of 4096 Bytes for SST45VF512, 32 sectors of 4096 Bytes for the SST45VF010 and 64 sectors of 4096 Bytes for the SST45VF020. The memory is accessed for Read or Erase/Program by the SPI bus compatible serial protocol. The bus signals are: serial data input (SI), serial data output (SO), serial clock (SCK), write protect (WP#), chip enable (CE#), and hardware reset (RESET#).

The SST45VFxxx devices are offered in 8-pin SOIC package. See Figure 1 for the pinout.

Device Operation

The SST45VFxxx uses bus cycles of 8 bits each for commands, data, and addresses to execute operations. The operation instructions are listed in Table 2.

All instructions are synchronized off a high to low transition of CE#. The first low to high transition on SCK will initiate the instruction sequence. Inputs will be accepted on the rising edge of SCK starting with the most significant bit. Any low to high transition on CE# before the input instruction completes will terminate any instruction in progress and return the device to the standby mode.

Read

The Read operation outputs the data in order from the initial accessed address. While SCK is input, the address will be incremented automatically until end (top) of the address space, then the internal address pointer automatically increments to beginning (bottom) of the address space (00000H), and data out stream will continue. The read data stream is continuous through all addresses until terminated by a low to high transition on CE#.

Sector/Chip-Erase Operation

The Sector-Erase operation clears all bits in the selected sector to "FF". The Chip-Erase instruction clears all bits in the device to "FF".

Byte-Program Operation

The Byte-Program operation programs the bits in the selected byte to the desired data. The selected byte must be in the erased state ("FF") when initiating a Program operation. The data is input from bit 7 to bit 0 in order.

Software Status Operation

The Status operation determines if an Erase or Program operation is in progress. If bit 0 is at a "0" an Erase or Program operation is in progress, the device is busy. If bit 0 is at a "1" the device is ready for any valid operation. The status read is continuous with ongoing clock cycles until terminated by a low to high transition on CE#.



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Reset

Reset will terminate any operation, e.g., Read, Erase and Program, in progress. It is activated by a high to low transition on the RESET# pin. The device will remain in reset condition as long as RESET# is low. Minimum reset time is 10µs. See Figure 14 for reset timing diagram. RESET# is internally pulled-up and could remain unconnected during normal operation. After reset, the device is in standby mode, a high to low transition on CE# is required to start the next operation.

An internal power-on reset circuit protects against accidental data writes. Applying a logic level low to RESET# during the power-on process then changing to a logic level high when V_{DD} has reached the correct voltage level will provide additional protection against accidental writes during power on.

Read SST ID/Read Device ID

The Read SST ID and Read Device ID operations read the JEDEC assigned manufacturer identification and the manufacturer assigned device identification codes. These codes may be used to determine the actual device resident in the system.

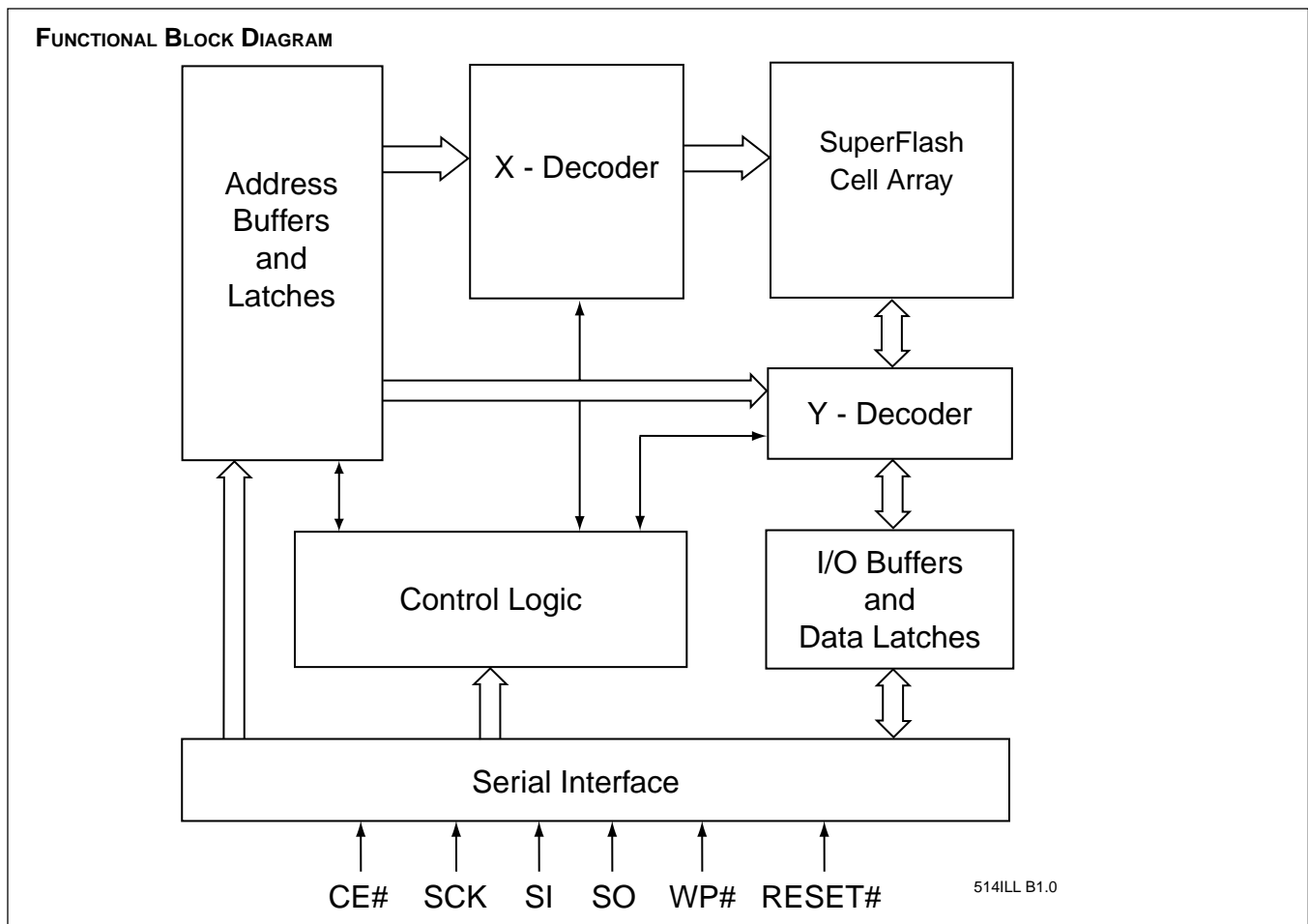
TABLE 1: PRODUCT IDENTIFICATION

| | Byte | Data |
|-------------------|--------|------|
| Manufacturer's ID | 0000 H | BF H |
| Device ID | | |
| SST45VF512 | 0001 H | 41 H |
| SST45VF010 | 0001 H | 45 H |
| SST45VF020 | 0001 H | 43 H |

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Write Protect

The WP# pin provides inadvertent write protection. The WP# pin must be held high for any Erase or Program operation. The WP# pin is "don't care" for all other operations. In typical use, the WP# pin is connected to V_{SS} with a standard pull-down resistor. WP# is then driven high whenever an Erase or Program operation is required. If the WP# pin is tied to V_{DD} with a pull-up resistor, then all operations may occur and the write protection feature is disabled. The WP# pin has an internal pull-up and could remain unconnected when not used.





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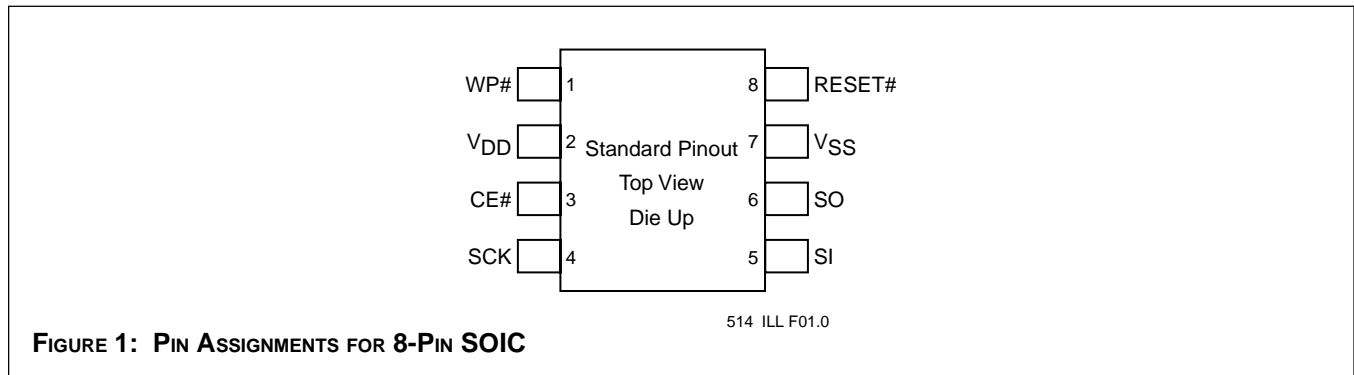


TABLE 2: PIN DESCRIPTION

| Symbol | Pin Name | Functions |
|-----------------|--------------------|---|
| SCK | Serial Clock | To provide the timing of the serial interface. Commands, addresses, or input data are latched on the rising edge of the clock input, while output data is shifted out on the falling edge of the clock input. |
| SI | Serial Data Input | To transfer commands, addresses, or data serially into the device. Inputs are latched on the rising edge of the serial clock. |
| SO | Serial Data Output | To transfer data serially out of the device. Data is shifted out on the falling edge of the serial clock. |
| CE# | Chip Enable | The device is enabled by a high to low transition on CE#. |
| WP# | Write Protect | To protect the device from unintentional Write (Erase or Program) operations. When WP# is low, all Erase and Program commands are ignored. When WP# is high, the device may be erased or programmed. This pin has an internal pull-up and could remain unconnected when not used. |
| RESET# | Reset | A high to low transition on RESET# will terminate any operation in progress and reset the internal logic to the standby mode. The device will remain in the reset condition as long as the RESET# is low. Operations may only occur when RESET# is high. This pin has an internal pull-up and could remain unconnected when not used. |
| V _{DD} | Power Supply | To provide power supply (2.7-3.6V). |
| V _{SS} | Ground | |

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TABLE 3: DEVICE OPERATION INSTRUCTIONS

| Bus Cycle | 1 | 2 | 3 | 4 | 5 | 6 | 7 and after |
|-----------------------------|---------|----------------------------------|---------------------------------|--------------------------------|-----------|-------|-------------|
| Operation/Type | Command | Address ¹ | Address | Address | Data | Dummy | Data |
| Read | FFH | A ₂₃ -A ₁₆ | A ₁₅ -A ₈ | A ₇ -A ₀ | X | X | Dout |
| Sector-Erase ² | 20H | A ₂₃ -A ₁₆ | A ₁₅ -A ₈ | X | D0H | X | |
| Chip-Erase | 60H | X | X | X | D0H | X | |
| Byte-Program | 10H | A ₂₃ -A ₁₆ | A ₁₅ -A ₈ | A ₇ -A ₀ | Din | X | |
| Software-Status | 9FH | Dout | | | | | |
| Read SST ID | 90H | X | X | A ₀ =0 | BFH | | |
| Read Device ID ³ | 90H | X | X | A ₀ =1 | Device ID | | |

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Notes:

- A₂₃-A₁₆ are "Don't Care" for SST45VF512, A₂₃-A₁₇ are "Don't Care" for SST45VF010, A₂₃-A₁₈ are "Don't Care" for SST45VF020.
- A₁₆-A₁₂ are used to determine sector address, A₁₁-A₈ are don't care.
- With A₁₅-A₁ = 0, SST45VF512 Device ID = 41H, is read with A₀ = 1.
With A₁₆-A₁ = 0, SST45VF010 Device ID = 45H, is read with A₀ = 1.
With A₁₇-A₁ = 0, SST45VF020 Device ID = 43H, is read with A₀ = 1.

TABLE 4: DEVICE OPERATION TABLE

| Operation | SI | SO | CE# ¹ | WP# | RESET# |
|--------------------|-----|------|------------------|------|--------|
| Read | X | Dout | Low | X | High |
| Sector-Erase | X | X | Low | High | High |
| Chip-Erase | X | X | Low | High | High |
| Byte-Program | Din | X | Low | High | High |
| Software-Status | X | Dout | Low | X | High |
| Reset ² | X | X | X | X | Low |
| Read SST ID | X | Dout | Low | X | High |
| Read Device ID | X | Dout | Low | X | High |

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Notes:

- A high to low transition on CE# will be required to start any device operation except for Reset.
- The RESET# low will return the device to standby and terminate any Erase or Program operation in progress.



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Absolute Maximum Stress Ratings (Applied conditions greater than those listed under “Absolute maximum Stress Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these conditions or conditions greater than those defined in the operational sections of this data sheet is not implied. Exposure to absolute maximum stress rating conditions may affect device reliability.)

| | |
|---|--------------------------|
| Temperature Under Bias | -55°C to +125°C |
| Storage Temperature | -65°C to +150°C |
| D. C. Voltage on Any Pin to Ground Potential | -0.5V to $V_{DD} + 0.5V$ |
| Transient Voltage (<20 ns) on Any Pin to Ground Potential | -1.0V to $V_{DD} + 1.0V$ |
| Package Power Dissipation Capability ($T_a = 25^\circ C$) | 1.0W |
| Surface Mount Lead Soldering Temperature (3 Seconds) | 240°C |
| Output Short Circuit Current ¹ | 50 mA |

OPERATING RANGE

| Range | Ambient Temp | V_{DD} |
|------------|----------------|----------|
| Commercial | 0 °C to +70 °C | 2.7-3.6V |

AC CONDITIONS OF TEST

| | |
|----------------------------|---------------|
| Input Rise/Fall Time | 5 ns |
| Output Load | $C_L = 30$ pF |
| See Figures 2 and 3 | |

TABLE 5: DC OPERATING CHARACTERISTICS $V_{DD} = 2.7-3.6V$

| Symbol | Parameter | Limits | | | Test Conditions |
|-----------|---|--------------|-----|---------|--|
| | | Min | Max | Units | |
| I_{DD} | Power Supply Current Read Program and Erase | | 20 | mA | $f = 10$ MHz $CE\# = V_{IL}$, $V_{DD} = V_{DD}$ Max. $CE\# = V_{IL}$, $V_{DD} = V_{DD}$ Max. |
| | | | 30 | mA | |
| I_{SB} | Standby Current | | 15 | μA | $CE\# = V_{IHC}$, $V_{DD} = V_{DD}$ Max. |
| I_{LI} | Input Leakage Current | | 1 | μA | $V_{IN} = GND$ to V_{DD} , $V_{DD} = V_{DD}$ Max. |
| I_{LO} | Output Leakage Current | | 1 | μA | $V_{OUT} = GND$ to V_{DD} , $V_{DD} = V_{DD}$ Max. |
| I_{IL} | Input Low Current ⁽²⁾ | | 360 | μA | WP#, RESET# = GND |
| V_{IL} | Input Low Voltage | | 0.8 | V | $V_{DD} = V_{DD}$ Min. |
| V_{IH} | Input High Voltage | $0.7 V_{DD}$ | | V | $V_{DD} = V_{DD}$ Max. |
| V_{IHC} | Input High Voltage (CMOS) | $V_{DD}-0.3$ | | V | $V_{DD} = V_{DD}$ Max. |
| V_{OL} | Output Low Voltage | | 0.2 | V | $I_{OL} = 100 \mu A$, $V_{DD} = V_{DD}$ Min. |
| V_{OH} | Output High Voltage | $V_{DD}-0.2$ | | V | $I_{OH} = -100 \mu A$, $V_{DD} = V_{DD}$ Min. |

Note: 1. Outputs shorted for no more than one second. No more than one output shorted at a time.
2. This parameter only applies to WP# and RESET# pins.

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TABLE 6: CAPACITANCE (Ta = 25 °C, f=1 Mhz, other pins open)

| Parameter | Description | Test Condition | Maximum |
|-------------------------------|------------------------|-----------------------|---------|
| C _{OUT} ¹ | Output Pin Capacitance | V _{OUT} = 0V | 12 pF |
| C _{IN} ¹ | Input Capacitance | V _{IN} = 0v | 6 pF |

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TABLE 7: RELIABILITY CHARACTERISTICS

| Symbol | Parameter | Minimum Specification | Units | Test Method |
|-----------------------------------|--|-----------------------|--------|---------------------|
| N _{END} ¹ | Endurance | 10,000 | Cycles | JEDEC Standard A117 |
| T _{DR} ¹ | Data Retention | 100 | Years | JEDEC Standard A103 |
| V _{ZAP_HBM} ¹ | ESD Susceptibility Human Body Model | 2000 | Volts | JEDEC Standard A114 |
| V _{ZAP_MM} ¹ | ESD Susceptibility Machine Model | 200 | Volts | JEDEC Standard A115 |
| I _{LTH} ¹ | Latch Up | 100 + I _{DD} | mA | JEDEC Standard 78 |

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Note: 1. This parameter is measured only for initial qualification and after a design or process change that could affect this parameter.

TABLE 8: AC OPERATING CHARACTERISTICS V_{DD} = 2.7-3.6V

| Symbol | Parameter | Limits | | |
|--------------------|-----------------------------|--------|-----|-------|
| | | Min | Max | Units |
| F _{CLK} | Serial Clock Frequency | | 10 | MHz |
| T _{SCKH} | Serial Clock High Time | 45 | | ns |
| T _{SCKL} | Serial Clock Low Time | 45 | | ns |
| T _{CES} | CE# Setup Time | 250 | | ns |
| T _{CEH} | CE# Hold Time | 250 | | ns |
| T _{CPH} | CE# High Time | 250 | | ns |
| T _{CHZ} | CE# High to High-Z Output | | 25 | ns |
| T _{CLZ} | CE# Low to Low-Z Output | 0 | | ns |
| T _{RLZ} | RESET# Low to High-Z Output | | 25 | ns |
| T _{DS} | Data In Setup Time | 20 | | ns |
| T _{DH} | Data In Hold Time | 20 | | ns |
| T _{OH} | Output Hold from SCK Change | 0 | | ns |
| T _V | Output Valid from SCK | | 35 | ns |
| T _{WPS} | Write Protect Setup Time | 10 | | ns |
| T _{WPH} | Write Protect Hold Time | 10 | | ns |
| T _{SE} | Sector-Erase | | 25 | ms |
| T _{SCE} | Chip-Erase | | 100 | ms |
| T _{BP} | Byte-Program | | 20 | µs |
| T _{RST} | Reset Pulse Width | 10 | | µs |
| T _{REC} | Reset Recovery Time | | 1 | µs |
| T _{PURST} | Reset Time After Power-Up | 10 | | µs |

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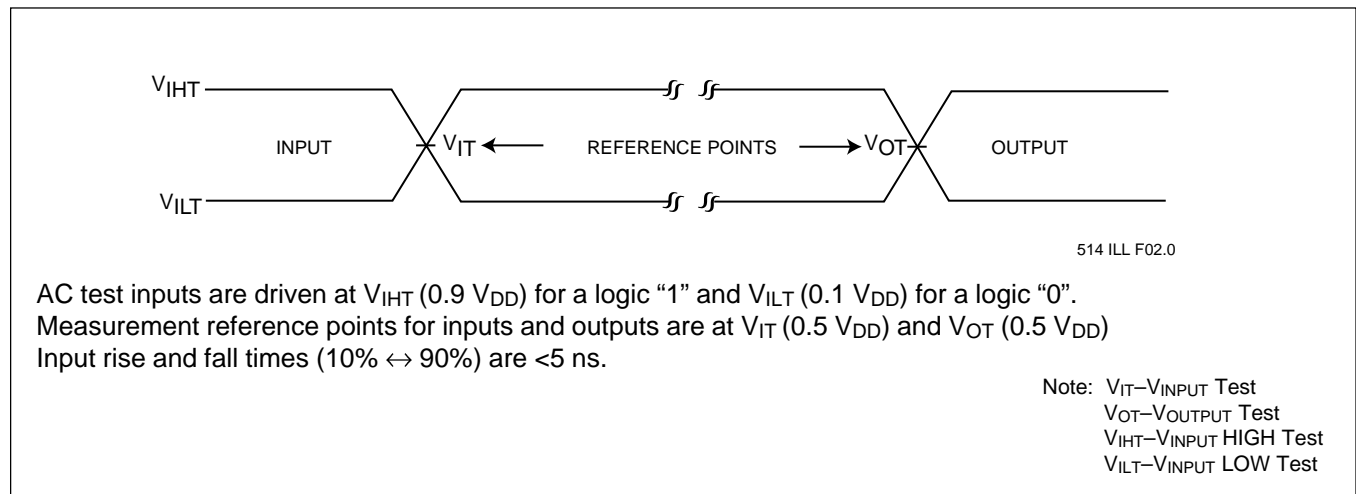


FIGURE 2: AC INPUT/OUTPUT REFERENCE WAVEFORMS

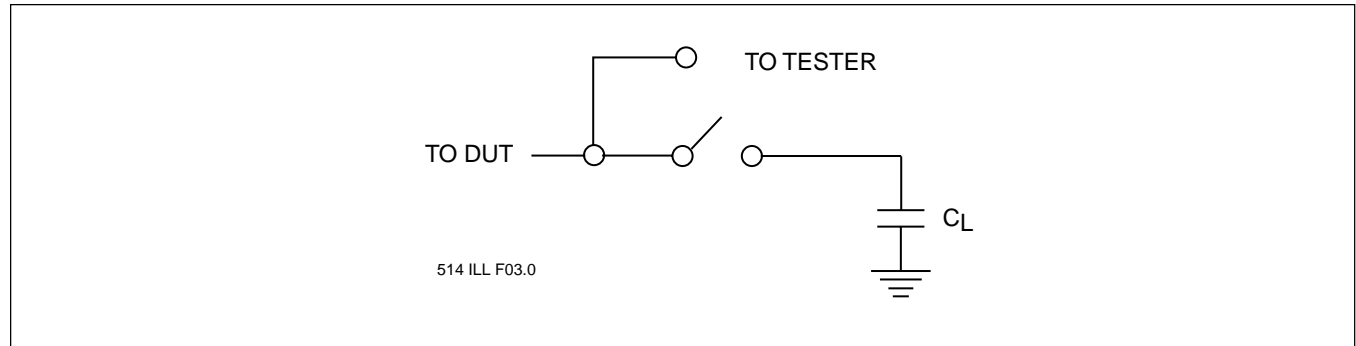
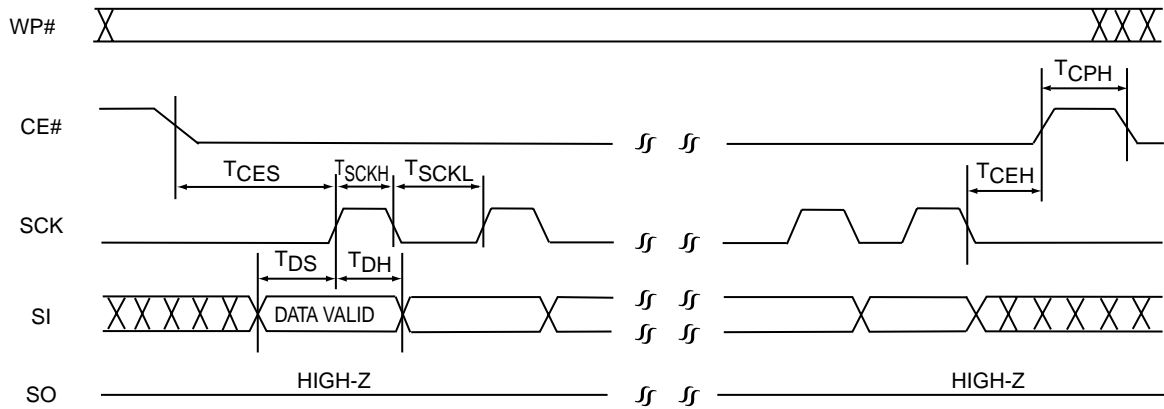
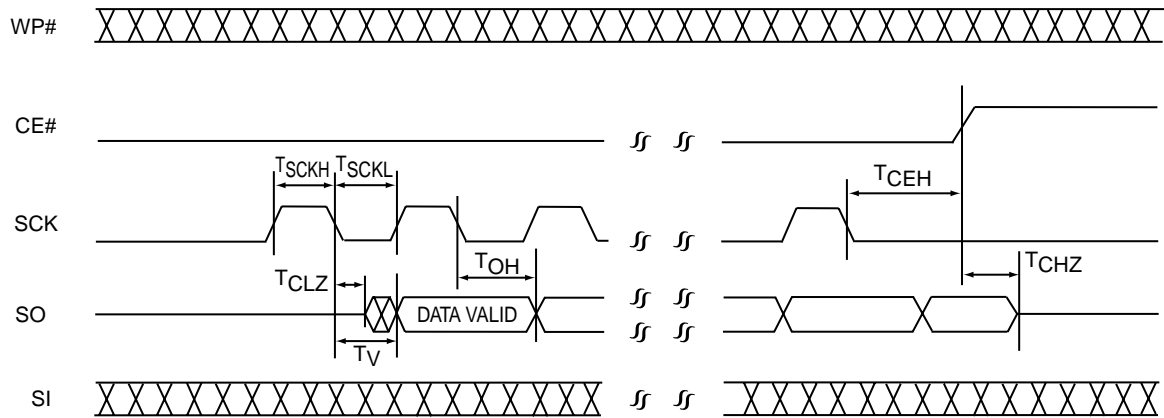


FIGURE 3: A TEST LOAD EXAMPLE



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FIGURE 4: SERIAL INPUT TIMING DIAGRAM (INACTIVE SERIAL CLOCK LOW - MODE 0)



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FIGURE 5: SERIAL OUTPUT TIMING DIAGRAM (INACTIVE SERIAL CLOCK LOW - MODE 0)



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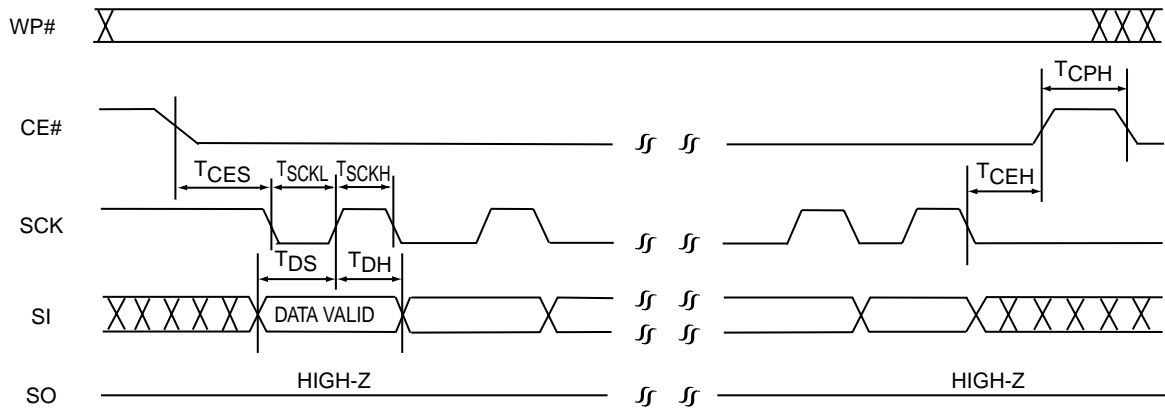


FIGURE 6: SERIAL INPUT TIMING DIAGRAM (INACTIVE SERIAL CLOCK HIGH - MODE 3)

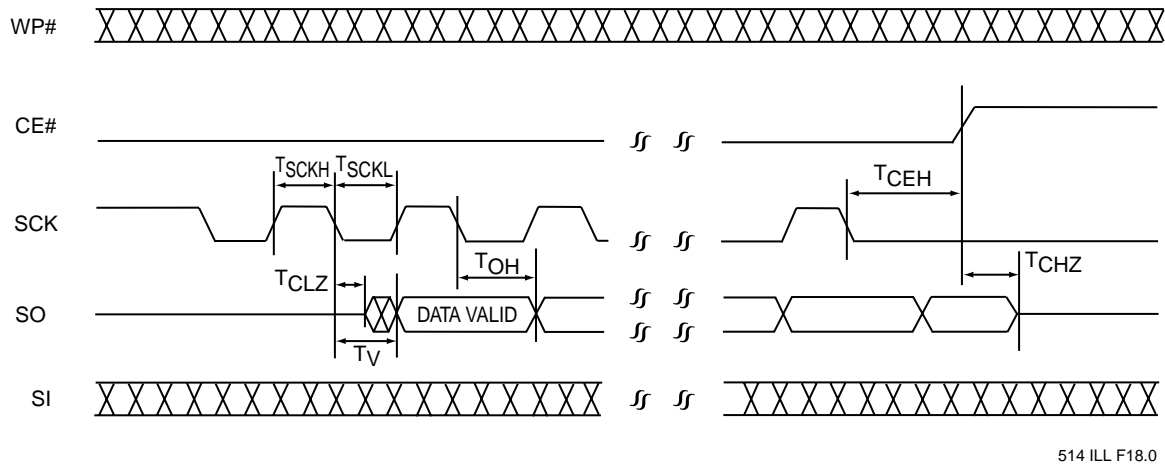


FIGURE 7: SERIAL OUTPUT TIMING DIAGRAM (INACTIVE SERIAL CLOCK HIGH - MODE 3)

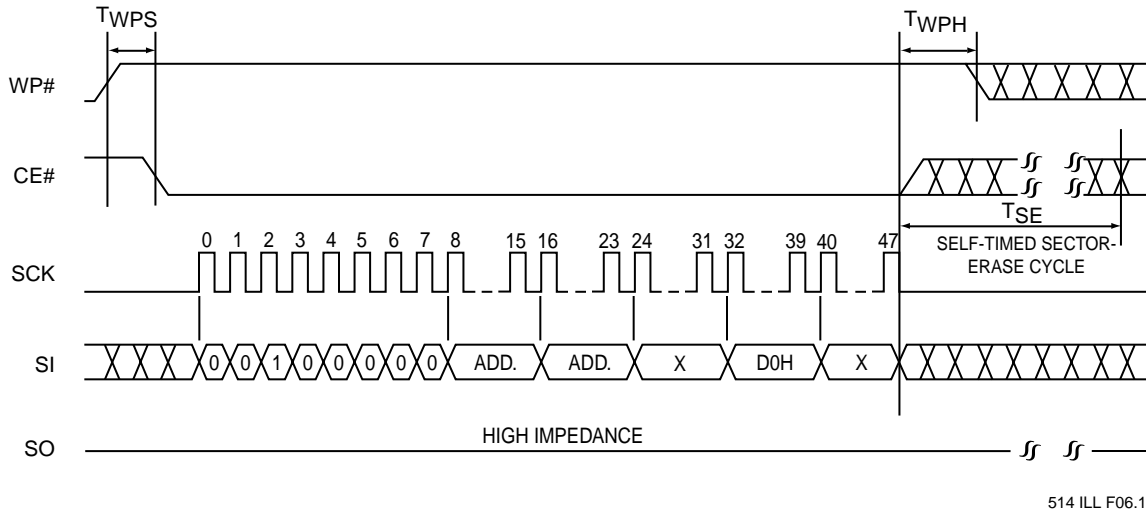


FIGURE 8: SECTOR-ERASE TIMING DIAGRAM

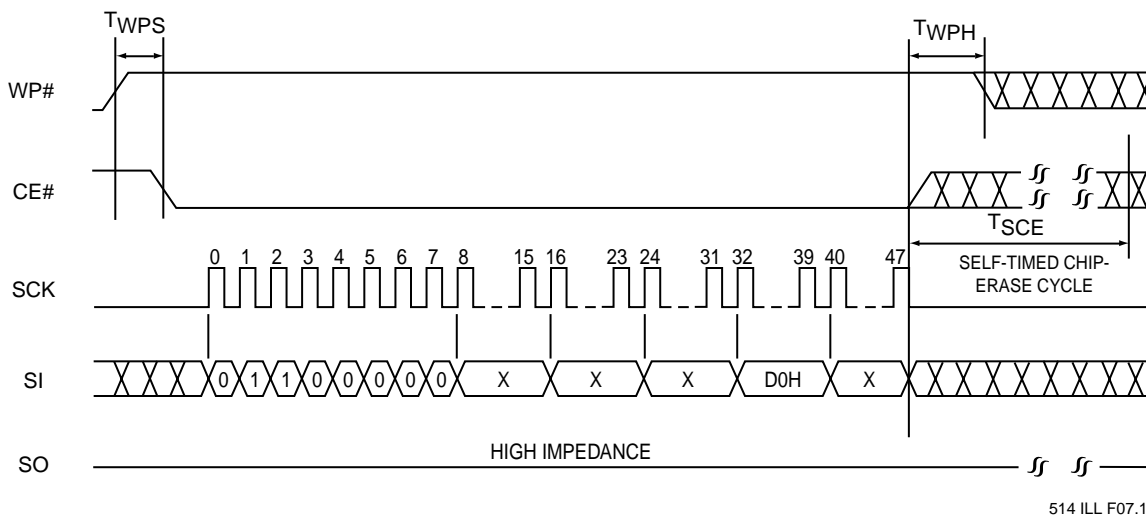
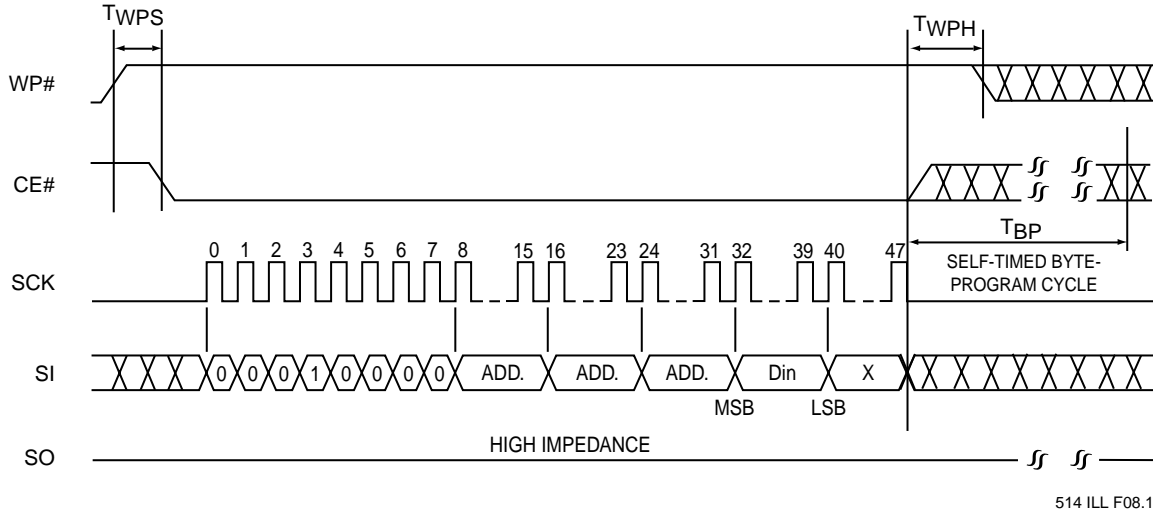


FIGURE 9: CHIP-ERASE TIMING DIAGRAM



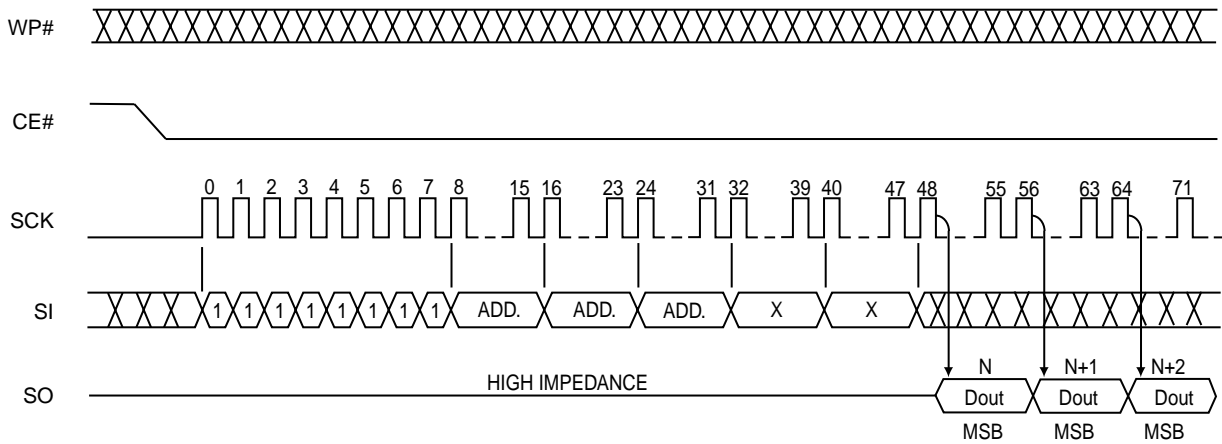
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FIGURE 10: BYTE-PROGRAM TIMING DIAGRAM



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FIGURE 11: READ TIMING DIAGRAM

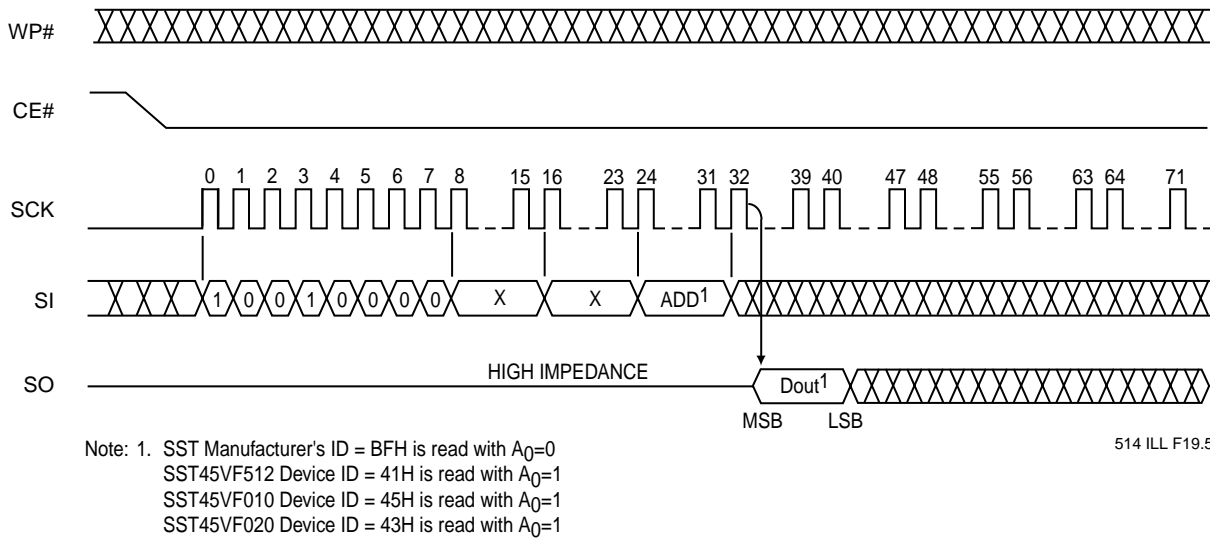


FIGURE 12: READ-ID TIMING DIAGRAM

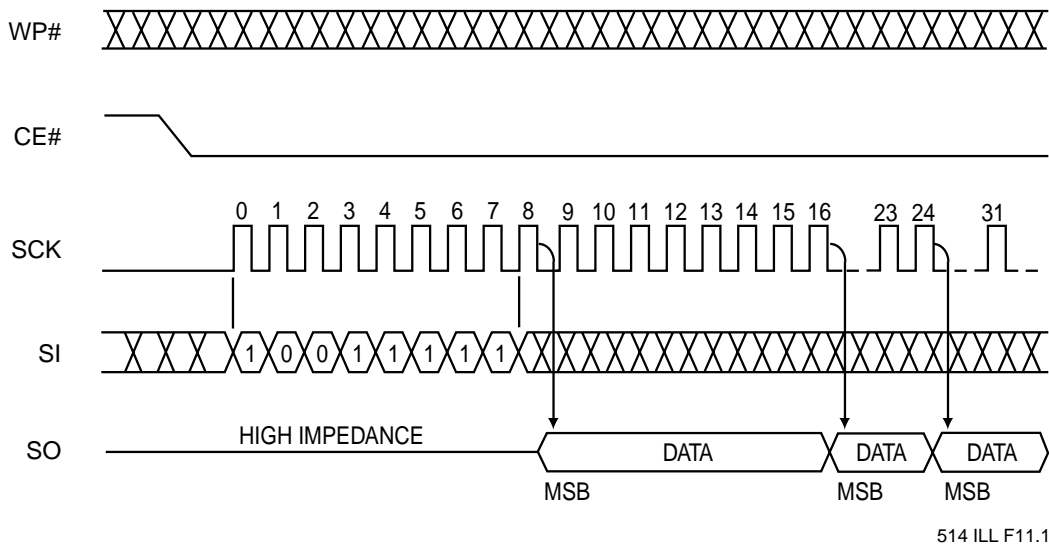
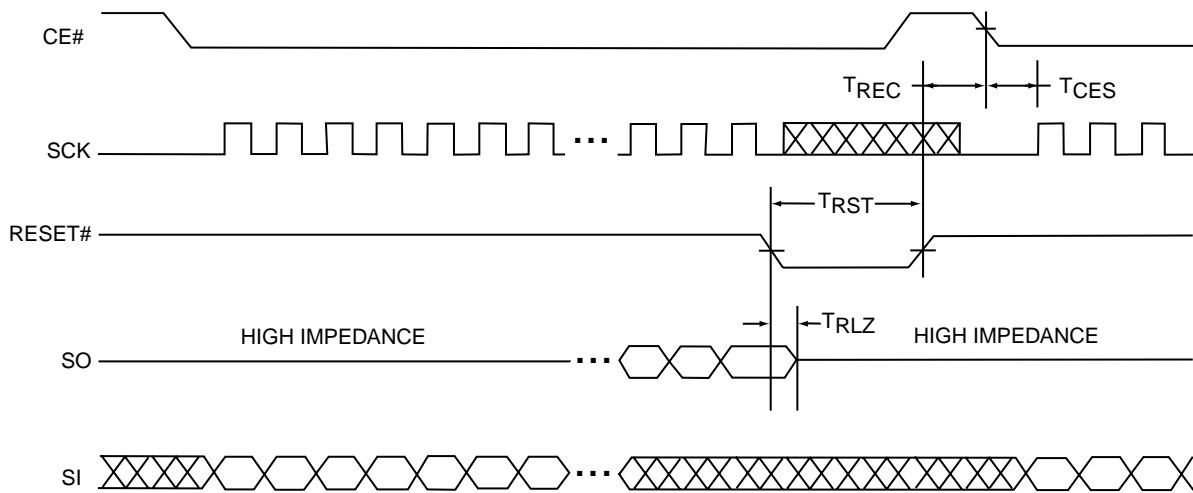


FIGURE 13: SOFTWARE-STATUS TIMING DIAGRAM



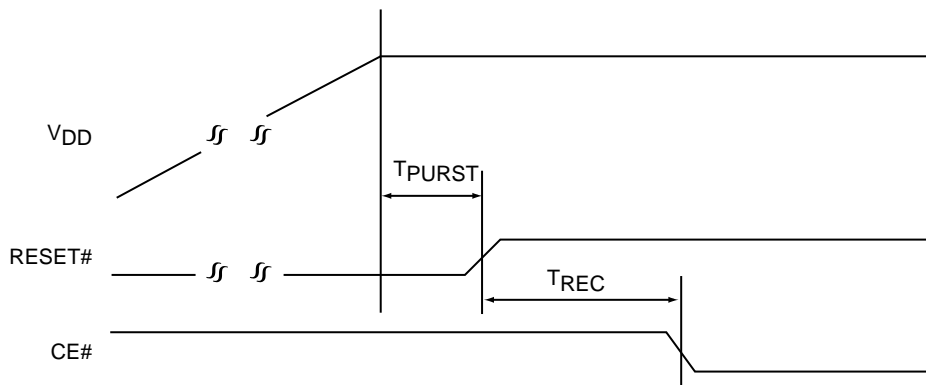
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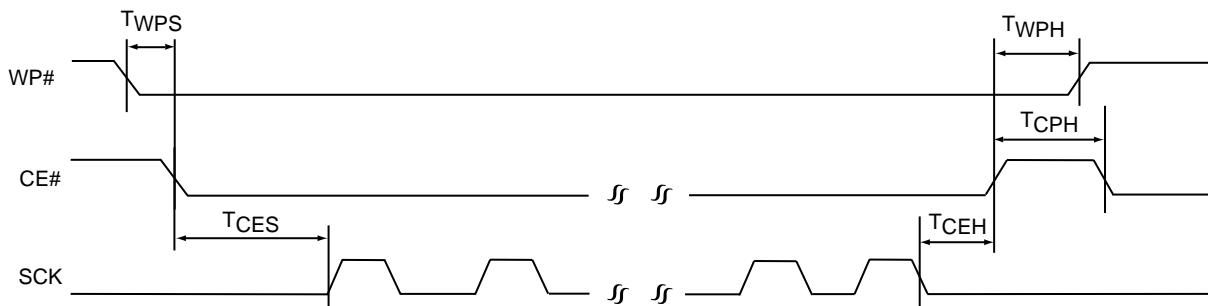
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FIGURE 14: RESET TIMING DIAGRAM (INACTIVE CLOCK POLARITY LOW SHOWN)



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FIGURE 15: POWER-ON RESET TIMING DIAGRAM



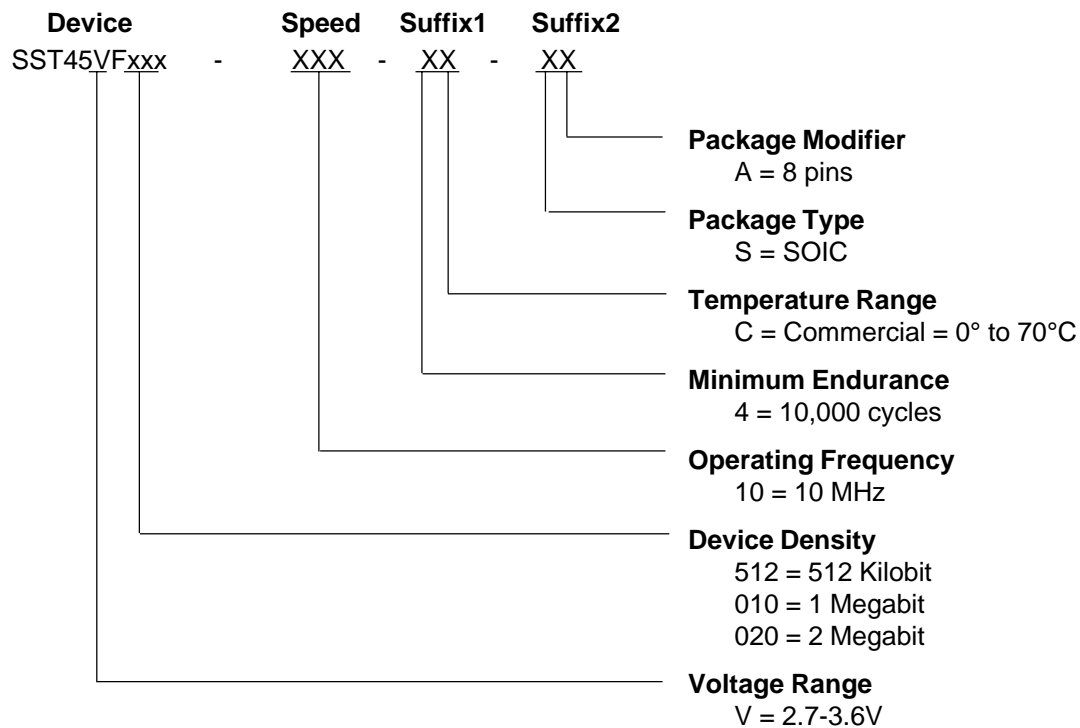
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FIGURE 16: WRITE PROTECT TIMING DIAGRAM



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SST45VF512 Valid combinations
SST45VF512-10-4C-SA

SST45VF010 Valid combinations
SST45VF010-10-4C-SA

SST45VF020 Valid combinations
SST45VF020-10-4C-SA

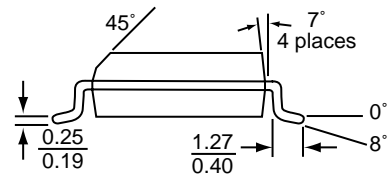
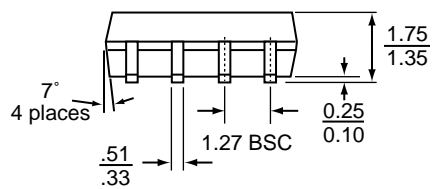
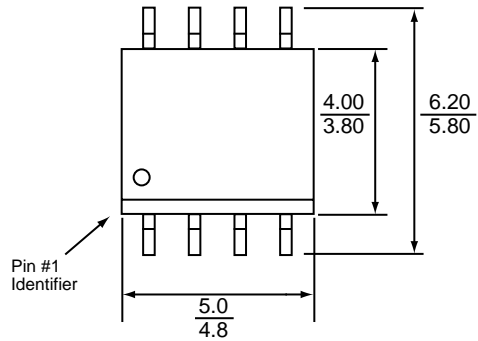
Example: Valid combinations are those products in mass production or will be in mass production. Consult your SST sales representative to confirm availability of valid combinations and to determine availability of new combinations.



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PACKAGING DIAGRAMS



8.soic-SA-ILL.3

- Note:
1. Complies with JEDEC publication 95 MS-012 AA dimensions, although some dimensions may be more stringent.
 2. All linear dimensions are in millimeters (min/max).
 3. Coplanarity: 0.1 (\pm .05) mm.

8-PIN SMALL OUTLINE INTEGRATED CIRCUIT PACKAGE (SOIC)

SST PACKAGE CODE: SA



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